

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/555,956	KRUMPELMANN ET AL.	
		Examiner	Art Unit	Page 1 of 1
		YUAN L. CHEN	4193	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,674,169	10-1997	Yang, Tai-Her	483/32
*	B	US-6,314,883	11-2001	Wech, Erich	101/248
*	C	US-5,551,339	09-1996	Schadlich et al.	101/216
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	EP 1205300 A1	05-2002	European Patent	IKEDA et al.	
*	O	DE 19832892 A1	01-2000	Germany	HICKER et al.	
*	P	EP 0835753 A1	04-1998	European Patent	Siler et al.	
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.